



Sheet 1 of 1

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)	ATTORNEY DOCKET NO.	APPLICATION NO.
	1391.1056	10/786,083
	FIRST NAMED INVENTOR	
	Ching Y. Suen et al.	
	FILING DATE	GROUP ART UNIT
	February 26, 2004	2624

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	TRANSLATION YES NO		ABSTRACT
	AG	2002-140706	05/17/2002	Japan	X		
	AH	1-250184	10/05/1989	Japan		X	Yes
	AI						
	AJ						
	AK						
	AL						

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

			TRANSLATION YES NO	
	AM	Hiroshi Murase, "Parametric Eigenspace Method for Image Recognition", TECHNICAL SURVEY, 2002, Vol. 85, No. 4, pp. 252-258.		X

EXAMINER	DATE CONSIDERED
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>	

**ATTACHMENT 1(e)****EXPLANATIONS OF RELEVANCY
OF REFERENCES**

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Japanese Patent Office Action, mailed July 31, 2007 and issued in corresponding Japanese Patent Application No. 2003-313367 cites Reference AM and Japanese Patent Publication Nos. 2002-140706 (Reference AG) and 1-250184 (Reference AH).



ATTACHMENT 1(g)

LIST OF ADDITIONAL SUBMITTED DOCUMENTS

ATTORNEY DOCKET NO.	APPLICATION NO.
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The following document(s) is/are listed in accordance with the duty of disclosure provisions of 37 CFR § 1.56, so that the Examiner may consider same should he deem any thereof to be material to examination of the subject application.

It is requested that the Examiner acknowledge his consideration of document(s) below-listed by initialing same in the space provided adjacent each such application and that the Examiner sign and date this form at the bottom thereof to confirm such consideration having been given.

This submission in no way represents an admission that any of the information listed herein constitutes prior art with respect to the subject application; and unless and until such prior art status is established, this submission is not a request that the information presented herein be printed on the face of any patent issuing from the subject application in which this information is being filed.

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
	AA						
	AB						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION	
							YES	NO
	AC							
	AD							

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

			TRANSLATION	
			YES	NO
	AE	Japanese Patent Office Action, mailed July 31, 2007 and issued in corresponding Japanese Patent Application No. 2003-313367		X

EXAMINER

DATE CONSIDERED

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